

N Channel MOSFET



Lead Free Package and Finish

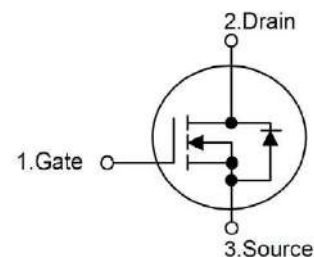
Applications:

- Switch Mode Power Supply(SMPS)
- Uninterruptible Power Supply(UPS)
- PFC stages for server & telecom

ID	R _{DS(ON)} (Typ)	V _{DSS}
4A	1.8Ω	600V

Features:

- Fast switching speed
- 100% avalanche tested
- Improved dv/dt capability



Ordering Information

Not to Scale

Part Number	Package	Marking
RS4N60F	TO-220F	RS4N60F

Absolute Maximum Ratings Tc=25°C unless otherwise specified

Symbol	Parameter	RS4N60F	Units
V _{DSS}	Drain-to-Source Voltage	600	V
I _D	Continuous Drain Current (T _C = 25°C)	4	A
	Continuous Drain Current (T _C = 100°C)	1.8	
I _{DM}	Pulsed Drain Current (Note*1)	16	
P _D	Power Dissipation(T _C =25°C)	20	W
V _{GS}	Gate-to-Source Voltage	±30	V
E _{AS}	Single Pulse Avalanche Engergy (Note*2)	88	mJ
I _{AR}	Avalanche Current (Note*1)	4.2	A
E _{AR}	Repetitive Avalanche Engergy (Note*1)	53	mJ
T _L TPKG	Maximum Temperature for Soldering	300 260	°C
	Leads at 0.063in(1.6mm)from Case for 10 seconds		
	Package Body for 10 seconds		
T _J and T _{STG}	Operating Junction and Storage Temperature Range	-55 to 150	

*Drain Current Limited by Maximum Junction Temperature

Caution:Stresses greater than those listed in the“Absolute Maximum Ratings”Table may cause permanent damage to the device.

Thermal Resistance

Symbol	Parameter	RS4N60F	Units	Test Conditions
RθJC	Junction-to-Case	5	°C/W	Drain lead soldered to water cooled heatsink,PD Adjusted for a peak junction temperature of +150°C.
RθJA	Junction-to-Ambient	62.5		1 cubic foot chamber,free air.

OFF Characteristics $T_J=25^{\circ}\text{C}$ unless otherwise specified

Symbol	Parameter	Min.	Typ.	Max.	Units	Test Conditions
BVDSS	Drain-to-source Breakdown Voltage	600	--	--	V	$V_{GS} = 0V, I_D = 250\mu A, T_J = 25^{\circ}\text{C}$
		--	600	--	V	$V_{GS} = 0V, I_D = 250\mu A, T_J = 150^{\circ}\text{C}$
IDSS	Drain-to-Source Leakage Current	--	--	1.0	μA	$V_{DS}=600V, V_{GS}=0V$
IGSS	Gate-to-Source Forward Leakage	--	--	100	nA	$V_{GS}=+30V, V_{DS}=0V$
	Gate-to-Source Reverse Leakage	--	--	-100		$V_{GS}=-30V, V_{DS}=0V$

ON Characteristics $T_J=25^{\circ}\text{C}$ unless otherwise specified

Symbol	Parameter	Min.	Typ.	Max.	Units	Test Conditions
RDS(on)	Static Drain-to-Source On-Resistance	--	1.80	2.20	Ω	$V_{GS}=10V, I_D=2A$
VGS(TH)	Gate Threshold Voltage	3.0	--	4.0	V	$V_{GS}=V_{DS}, I_D=250\mu A$

Resistive Switching Characteristics Essentially independent of operating temperature

Symbol	Parameter	Min.	Typ.	Max.	Units	Test Conditions
td(ON)	Turn-on Delay Time	--	36	--	ns	$V_{DS}=250V$ $I_D=4A$ $R_G=25\Omega$ $V_{GS}=10V$
trise	Rise Time	--	15	--		
td(OFF)	Turn-OFF Delay Time	--	90	--		
tfall	Fall Time	--	17	--		

Dynamic Characteristics Essentially independent of operating temperature

Symbol	Parameter	Min.	Typ.	Max.	Units	Test Conditions
Ciss	Input Capacitance	--	537	--	pF	$V_{GS}=0V$ $V_{DS}=100V$ $f=1.0\text{MHz}$
Coss	Output Capacitance	--	55.0	--		
Crss	Reverse Transfer Capacitance	--	5.0	--		
Qg	Total Gate Charge	--	16.0	--	nC	$V_{DS}=480V$ $I_D=4A$ $V_{GS}=10V$
Qgs	Gate-to-Source Charge	--	3.0	--		
Qgd	Gate-to-Drain("Miller") Charge	--	8.0	--		

Source-Drain Diode Characteristics

Symbol	Parameter	Min.	Typ.	Max.	Units	Test Conditions
IS	Continuous Source Current	--	--	4	A	Integral pn-diode in MOSFET
ISM	Maximum Pulsed Current	--	--	16	A	
VSD	Diode Forward Voltage	--	0.9	1.4	V	IS=4A, VGS=0V Tj=25°C
trr	Reverse Recovery Time	--	320	--	nS	VGS=0V IS=4A, di/dt=100A/μs
Qrr	Reverse Recovery Charge	--	1.1	--	μC	

Notes:

*1.Repetitive rating;pulse width limited by maximum junction temperature.

*2. IAS = 4A, VDD = 50V, RG = 25Ω, Starting TJ = 25°C Pulse width tp limited by Tj,max

Typical Feature curve T_J=25°C, unless otherwise noted

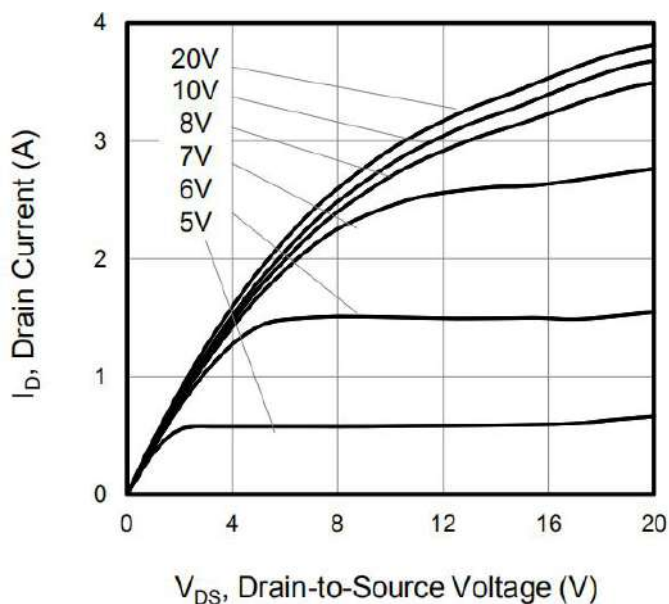
Figure 1. Output Characteristics (T_J = 25°C)

Figure2. Body Diode Forward Voltage

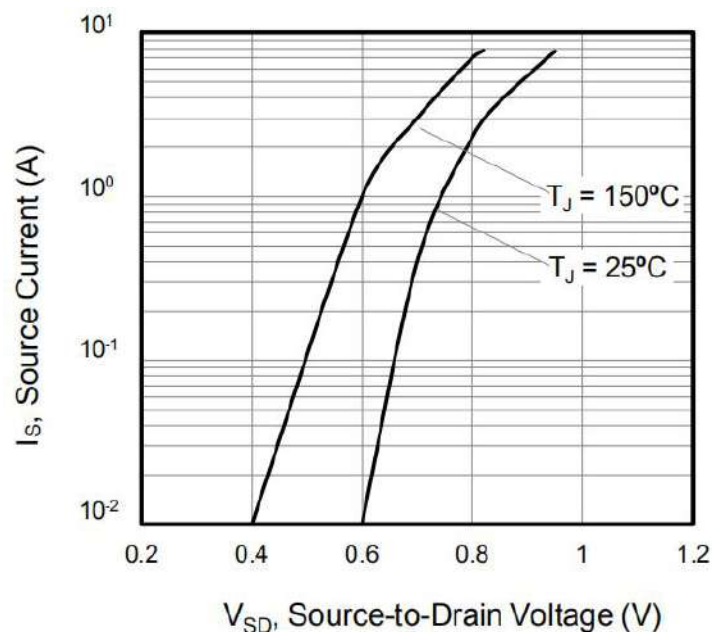


Figure 3. Drain Current vs. Temperature

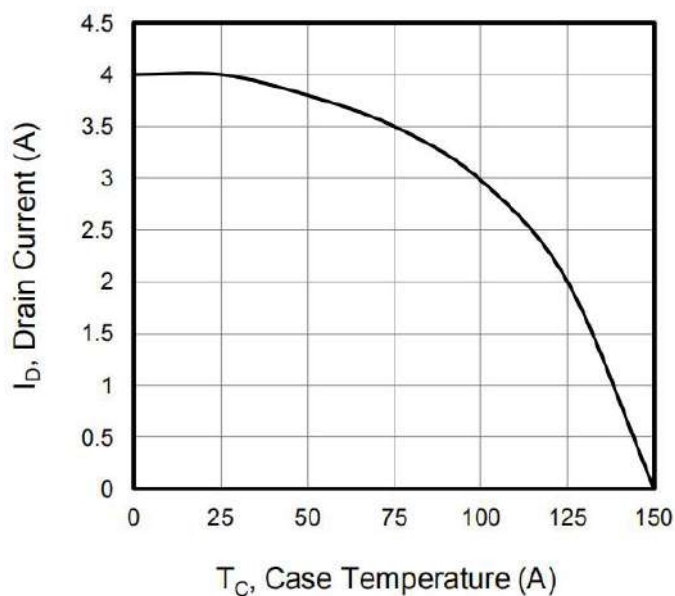


Figure 4. Power Dissipation vs. Temperature

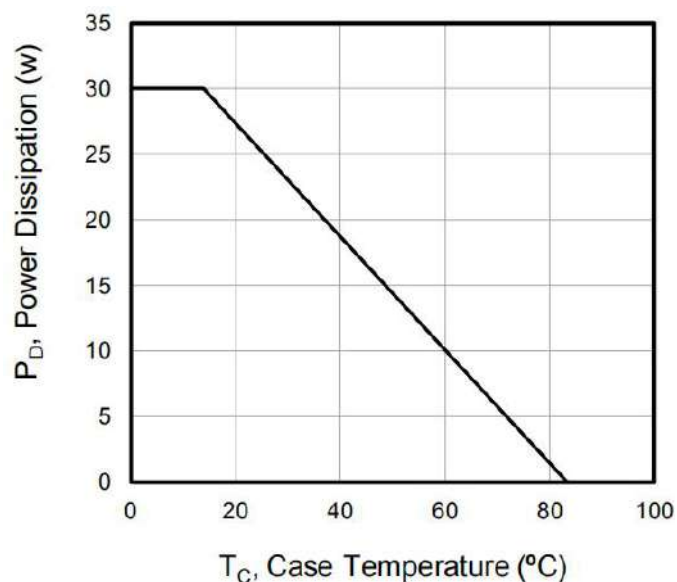


Figure 5. Transfer Characteristics

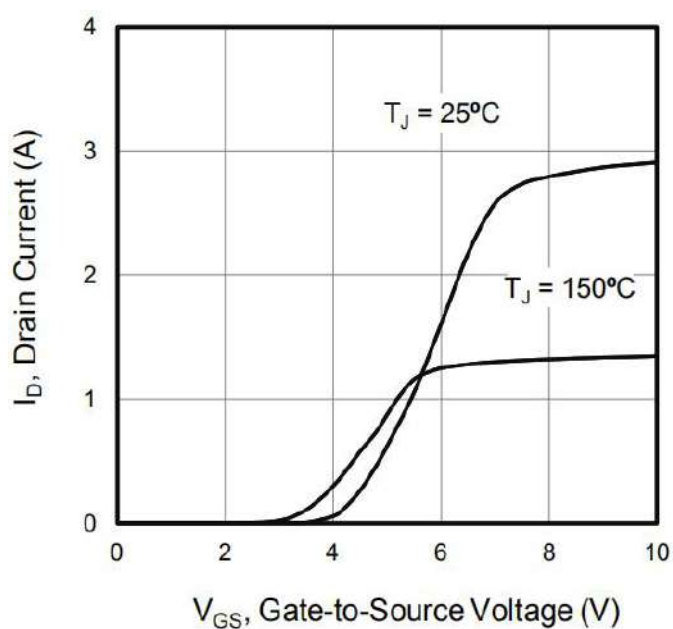


Figure 6. On-Resistance vs. Temperature

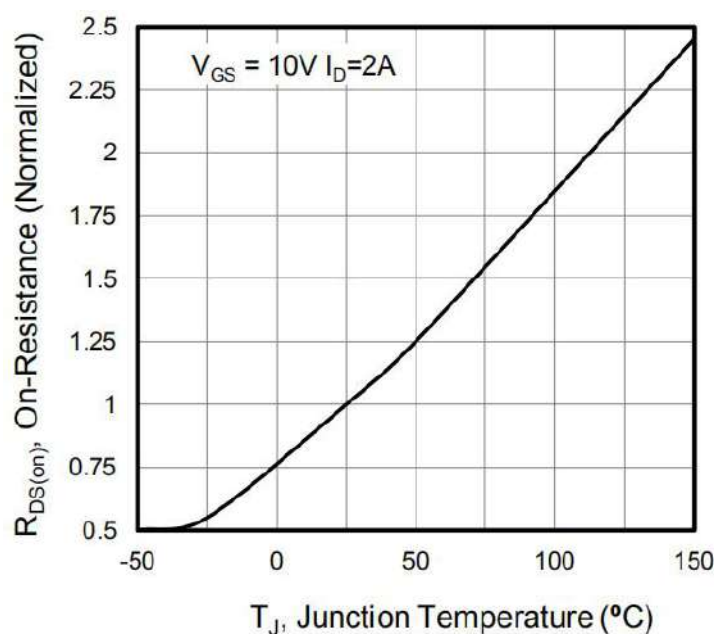


Figure 7. Capacitance

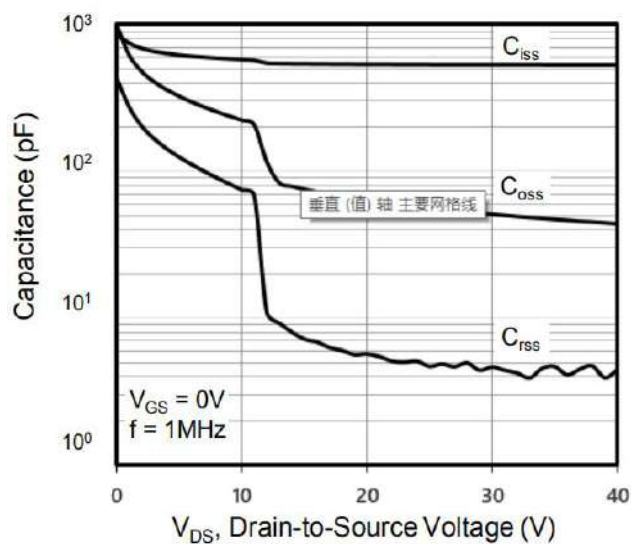
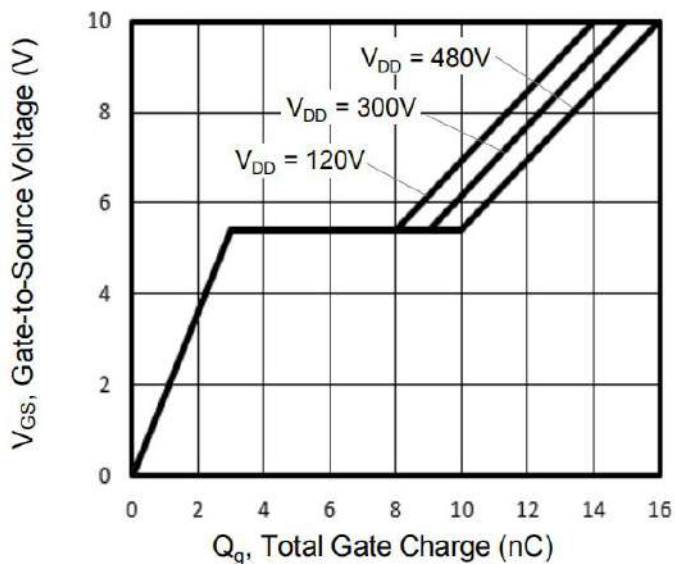
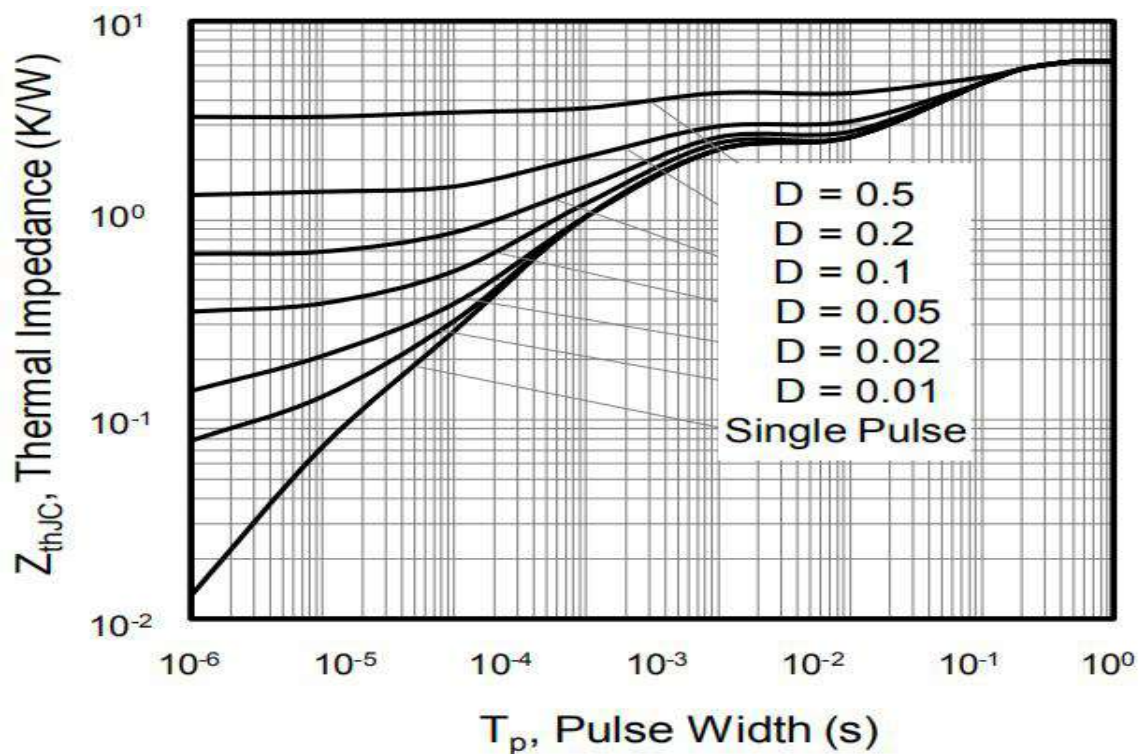


Figure 8. Gate Charge

Figure 9. Transient Thermal Impedance
TO-220F

Test Circuits and Waveforms

Figure A: Gate Charge Test Circuit and Waveform

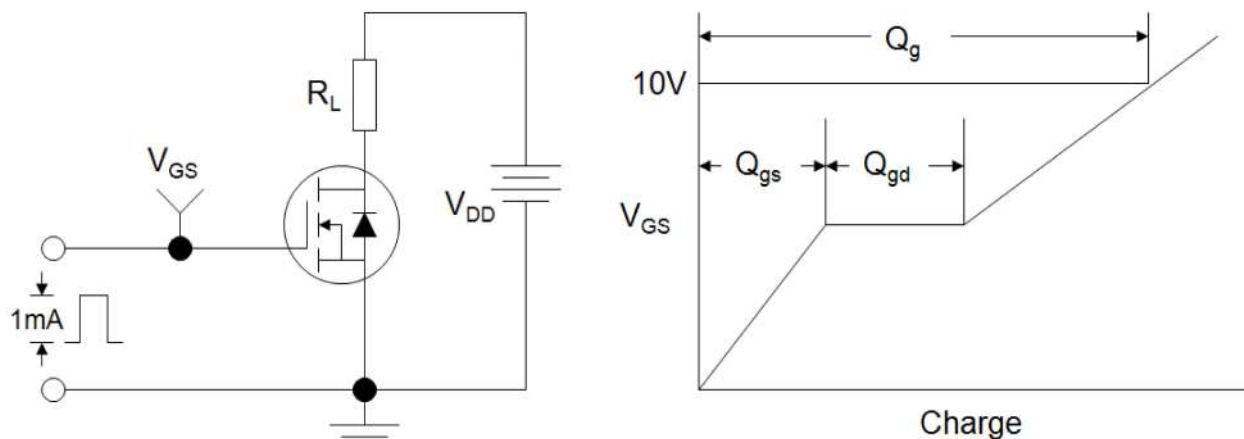


Figure B: Resistive Switching Test Circuit and Waveform

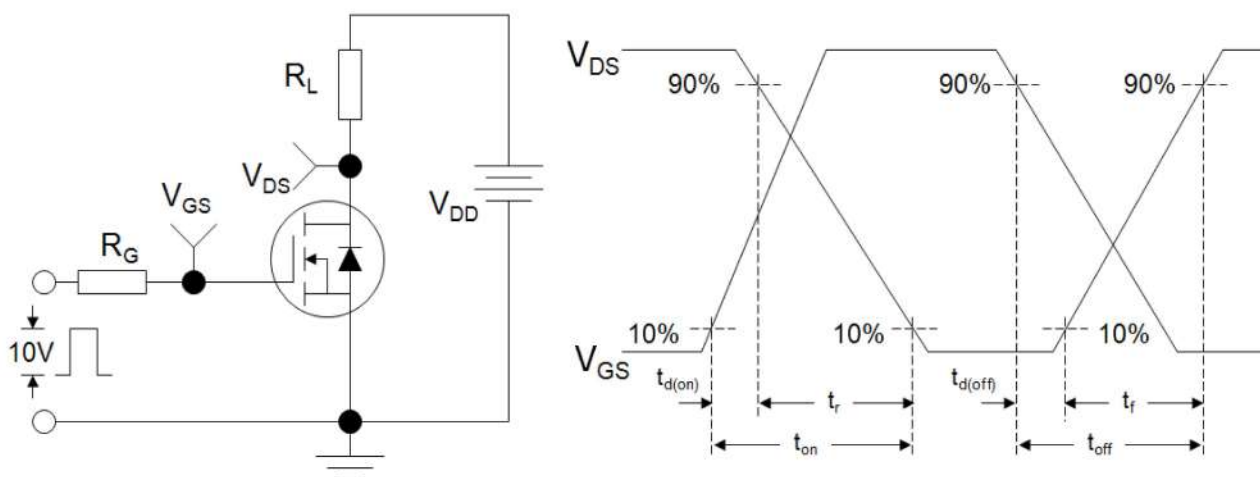
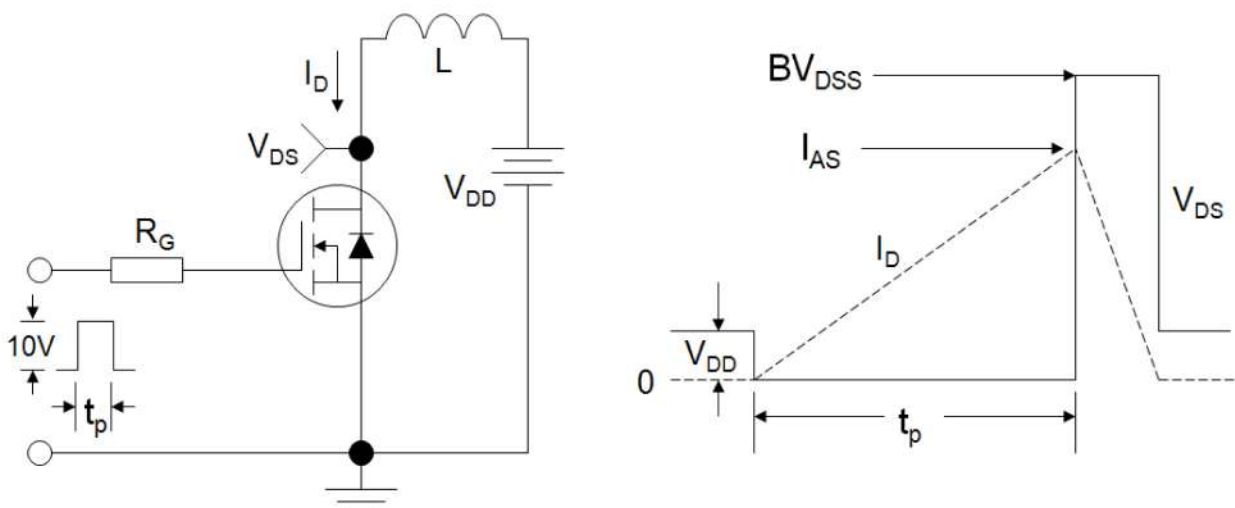


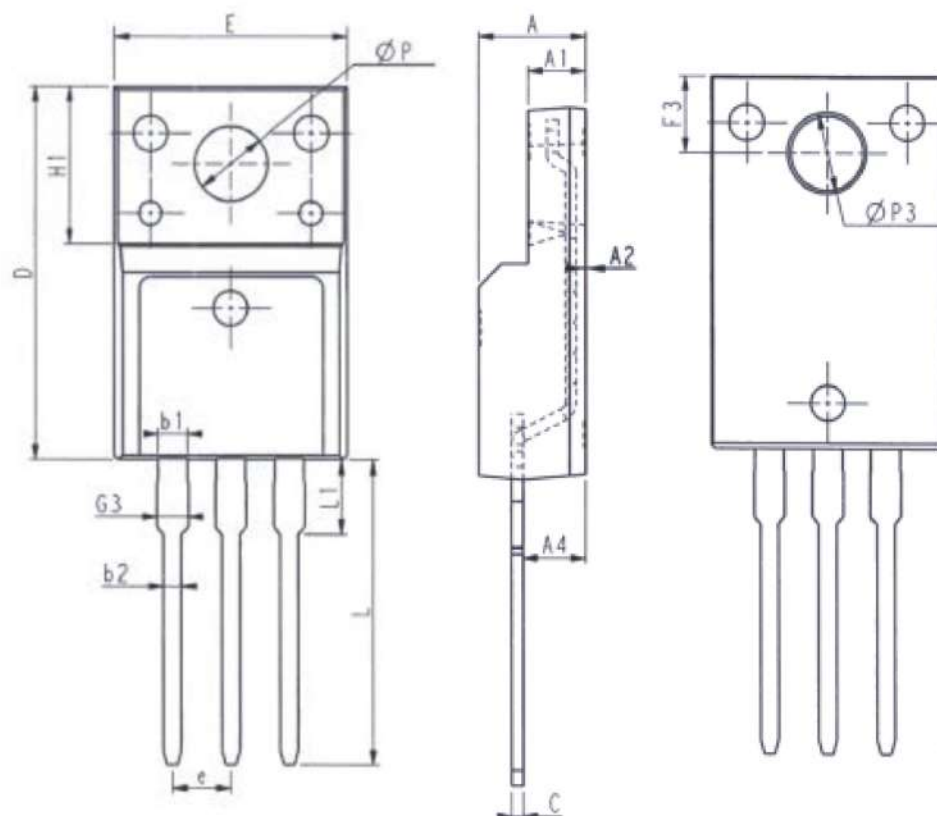
Figure C: Unclamped Inductive Switching Test Circuit and Waveform



Package outline drawing

Unit:mm

TO-220F



Unit: mm		
Symbol	Min.	Max.
E	9.96	10.36
A	4.50	4.90
A1	2.34	2.74
A2	0.30	0.60
A4	2.56	2.96
c	0.40	0.65
D	15.57	16.17
H1	6.70REF	
e	2.54BSC	

Unit: mm		
Symbol	Min.	Max.
L	12.68	13.28
L1	2.93	3.13
P	3.03	3.38
P3	3.15	3.65
F3	3.15	3.45
G3	1.25	1.55
b1	1.18	1.43
b2	0.70	0.95

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